

TEST REPORT

Applicant: Powerstick.com Inc.

39 Camelot Drive, Ottawa, Ontario CANADA, K2G Address:

5W6

Equipment Type: Power Snap

Model Name: Power Snap

Brand Name: powerstick.com

FCC ID: 2AITN-POWERSNAP

47 CFR Part 15 Subpart B

Test Standard:

ANSI C63.4-2014

Nov. 29, 2024 **Sample Arrival Date:**

Test Date: Nov. 29, 2024

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ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

Checked by: Xia Long Tested by: Xiao Tangqi Approved by: Sunny Zou

(Technical Director)

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Revision History

Version

Issue Date

Revisions

Rev. 01 Dec. 30

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Initial Issue

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.		
Address	Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road,		
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China		
Phone Number	+86 755 6685 0100		

1.2 Test Location

Name Shenzhen BALUN Technology Co., Ltd.			
	☑ Block B, 1/F, Baisha Science and Technology Park, Shahe Xi		
	Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China		
Location	☐ 1/F, Building B, Ganghongji High-tech Intelligent Industrial Park,		
	No. 1008, Songbai Road, Yangguang Community, Xili Sub-district,		
	Nanshan District, Shenzhen, Guangdong Province, P. R. China		
A core ditation Cortificate	The laboratory is a testing organization accredited by FCC as a		
Accreditation Certificate	accredited testing laboratory. The designation number is CN1196.		



2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	Powerstick.com Inc.
Address	39 Camelot Drive, Ottawa, Ontario CANADA, K2G 5W6

2.2 Manufacturer Information

Manufacturer	Powerstick.com Inc.
Address	39 Camelot Drive, Ottawa, Ontario CANADA, K2G 5W6

2.3 General Description for Equipment under Test (EUT)

EUT Name	Power Snap
Model Name Under Test	Power Snap
Series Model Name	N/A
Description of Model	NI/A
name differentiation	N/A
Hardware Version	N/A
Software Version	N/A
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.4 Ancillary Equipment

Note: Not applicable.

2.5 Technical Information

Network and Wireless connectivity	N/A
Classification of equipment	Class B
The highest internal frequency of EUT	Below 108 MHz



3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
	ANSI C63.4-2014	American National Standard for Methods of
		Measurement of Radio-Noise Emissions from Low-
2		Voltage Electrical and Electronic Equipment in the
		Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Remark
1	Radiated Emission	15.109	Pass	
2	Conducted Emission, AC Ports	15.107	Pass	

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9 kHz-30 MHz)	3.2 dB
Radiated emissions (30 MHz-1 GHz)-966#4	4.4 dB



4 GENERAL TEST CONFIGURATIONS

4.1 Test Enclosure List

Description	Manufacturer	Model	Serial No.	Length	Description	Use
Adapter	OPPO	VC54GBCH	N/A	N/A	N/A	\boxtimes
Mobile Phone	Apple	iPhone 12 mini	N/A	N/A	N/A	\boxtimes
USB Cable	OPPO	N/A	N/A	1m	N/A	\boxtimes
Load	N/A	N/A	N/A	N/A	N/A	\boxtimes
Clamp	N/A	N/A	N/A	N/A	N/A	\boxtimes
Magnetic ring	Dongyang	DYR-2919- 100A	N/A	N/A	N/A	\boxtimes

4.2 Test Configurations

All test modes of EUT are listed in the table below.

Test Mode	Description
Configuration	
Mode 1	The Charging Test Mode
Wode 1	EUT + Adapter + USB Cable
Mode 2	The USB Discharging Test Mode
Mode 2	EUT + Load + USB Cable + Clamp
Mode 3	The Discharging Test Mode
iviode 3	EUT + Load + Clamp

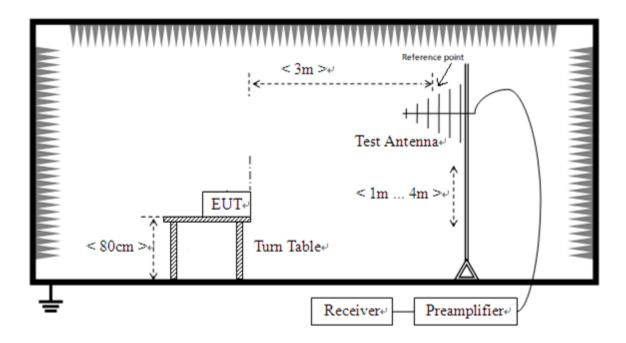
Test Case	Test Mode Configuration	Worst Mode
Radiated Emission	Mode 1~Mode 3	3
Conducted Emission, AC Ports	Mode 1	1

Note: All operation modes were tested, but only test data of the worst mode was presented in this report.



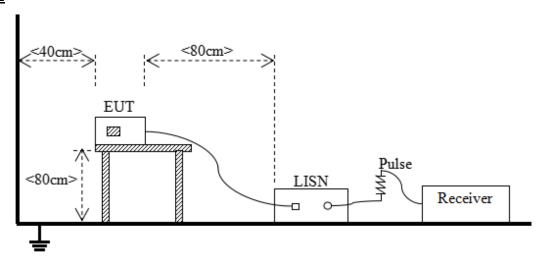
4.3 Test Setups

Test Setup 1



Radiated Emission (30 MHz-1 GHz)

Test Setup 2



Conducted Emissions, AC Ports



5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range	Class B	Class A (at 3 m)	
	Field Strength	Field Strength	Field Strength
(MHz)	(μV/m)	(dBµV/m)	(dBµV/m)
30 - 88	100	40	49.5
88 - 216	150	43.5	54
216 - 960	200	46	56.9
Above 960	500	54	60

NOTE:

- 1) Field Strength ($dB\mu V/m$) = 20*log [Field Strength ($\mu V/m$)].
- 2) In the emission tables above, the tighter limit applies at the band edges.
- 3) For 30 MHz to 1000 MHz, the CISPR quasi-peak is employed.

For above 1000 MHz, according to the requirements of FCC 15.35, unless otherwise specified, the limit on peak radio frequency emissions is 20 dB above the maximum permitted average emission limit applicable to the equipment under test.

Frequency range (GHz)		Class B (at 3 m)	Class A (at 3 m)		
	Field Strongth	Field Strength	Field Strength	Field Strength	Field Strength
	Field Strength (µV/m)	Average	Peak	Average	Peak
		(dBµV/m)	(dBµV/m)	(dBµV/m)	(dBµV/m)
1 - F _M	500	54	74	60	80

Note 1: The highest measurement frequency, F_M, in GHz, shall be determined as next Table.

Note 2: Average Class A limit at 3m L_{3m} is determined by the following conversion formula:

 $L_{3m} = L_{10m} + 20*log(d_{10m}/d_{3m})$

Where:

L_{3m} is Average Class A limit at 3m;

L_{10m} is Average Class A limit at 10m;

d_{10m} is Measurement distance in 10m;

d_{3m} is Measurement distance in 3m.

For this case: $L_{3m} = 49.5 + 20*log(10/3)=60 (dB\mu V/m)$.



Highest internal frequency (Fx)	Highest measurement frequency (F _M)
F _X ≤ 108 MHz	1 GHz
108 MHz ≤ F _X ≤ 500 MHz	2 GHz
500 MHz ≤ F _X ≤ 1 GHz	5 GHz
E. > 1 CUE	5 *Fx
F _X ≥ 1 GHz	or 40 GHz, whichever is lower.

Note: F_X is Highest frequency generated or used in the device or on which the device operates or tunes.

5.1.1.2 Test Setup

Refer to 4.3 section (test setup 1) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Radiated Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360°, and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for f ≥ 1 GHz, 100 kHz for f < 1 GHz

VBW ≥ RBW

Sweep = auto

Detector function = peak for f <1 GHz, peak & RMS Average for f ≥ 1 GHz

Trace = max hold

5.1.1.4 Test Result and Test Equipment List

Please refer to ANNEX A.1.



NOTE:

1. Results $(dB\mu V/m)$ = Reading $(dB\mu V)$ + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

- 2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) Amplifier Gain (dB)
- 3. Margin = Limit Results



5.1.2 Conducted Emission, AC Ports

5.1.2.1 Test Limit

	Class A				
Frequency range (MHz)	Quasi-peak	Average			
	(dBµV)	(dBµV)			
0.15 - 0.50	79	66			
0.50 - 30	73	60			

	Class B			
Frequency range (MHz)	Quasi-peak	Average		
	(dBµV)	(dBµV)		
0.15 - 0.50	66 to 56	56 to 46		
0.50 - 5	56	46		
5 - 30	60	50		

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.3 section test (test setup 2) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides $50 \Omega/50 \mu H$ of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW ≥ RBW

Sweep = 10ms

Detector function =peak & Average

Trace = max hold



5.1.2.4 Test Result and Test Equipment List

Please refer to ANNEX A.2.

NOTE:

1. Results $(dB\mu V)$ = Reading $(dB\mu V)$ + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

- 2. Factor = Insertion loss + Cable loss
- 3. Margin = Limit Results



ANNEX A TEST RESULTS

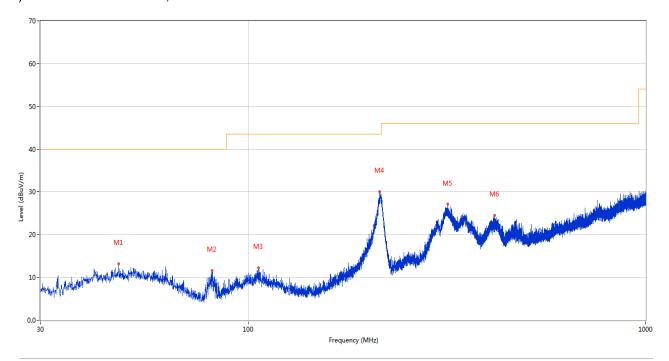
A.1 Radiated Emission

Note 1: The symbol of "--" in the table which means not application.

Sample No.	S01	Temperature	24.8℃
Humidity	56%RH	Pressure	101kPa
Test Engineer	Li Jianping	Test Date	2024.11.29

Test Mode 3

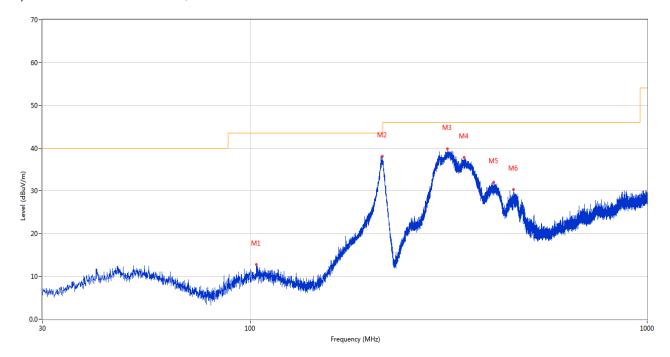
1) Test Antenna Vertical, 30 MHz - 1 GHz



No.	Frequency	Results	Factor	Limit	Margin	Detector	Table	Height	Antenna	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	(dB)		(Degree)	(cm)		
1	47.266	13.22	-24.86	40.0	26.78	Peak	263.80	200	Vertical	Pass
2	81.168	11.59	-31.48	40.0	28.41	Peak	137.50	200	Vertical	Pass
3	106.242	12.22	-26.63	43.5	31.28	Peak	173.90	100	Vertical	Pass
4	214.203	30.10	-26.15	43.5	13.40	Peak	89.80	200	Vertical	Pass
5	317.896	27.10	-22.90	46.0	18.90	Peak	105.60	100	Vertical	Pass
6	417.127	24.53	-20.15	46.0	21.47	Peak	89.80	200	Vertical	Pass



2) Test Antenna Horizontal, 30 MHz - 1 GHz



No.	Frequency	Results	Factor	Limit	Margin	Detector	Table	Height	Antenna	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	(dB)		(Degree)	(cm)		
1	103.623	12.80	-26.67	43.5	30.70	Peak	33.40	200	Horizontal	Pass
2	215.270	38.10	-26.08	43.5	5.40	Peak	188.10	100	Horizontal	Pass
3	314.113	39.82	-22.99	46.0	6.18	Peak	166.00	100	Horizontal	Pass
4	346.026	37.87	-21.29	46.0	8.13	Peak	181.70	100	Horizontal	Pass
5	410.822	31.98	-20.30	46.0	14.02	Peak	203.70	100	Horizontal	Pass
6	461.310	30.35	-19.13	46.0	15.65	Peak	170.80	200	Horizontal	Pass



Equipment Information									
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use			
Frequency Below 1 GHz									
EMI Receiver	Keysight	N9038A	MY53220118	2024.08.01	2025.07.31	\boxtimes			
Amplifier (30MHz-1GHz)	COM-MV	ZT30-1000M	B2017119082	2023.12.05	2024.12.04	\boxtimes			
Test Antenna- Bi-Log	SCHWARZB ECK	VULB 9163	9163-624	2024.07.06	2027.07.05				
Anechoic Chamber (#4)	ChangNing	9m*6m*6m	101	2023.03.04	2026.03.03				
Description	Supplier	Name	Version	1		Use			
Test Software	BALUN	BL410-E	V22.930	1		\boxtimes			



A.2 Conducted Emission, AC Ports

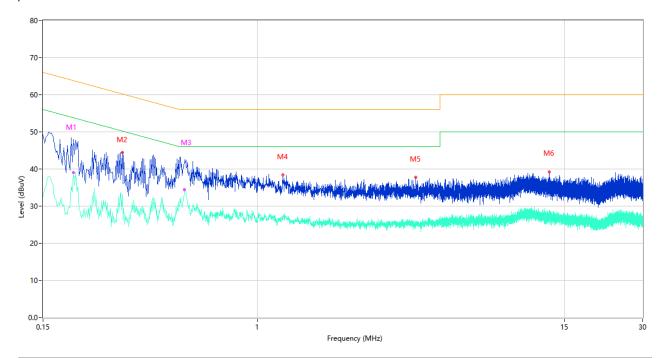
Note: Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. So, The configuration 120 VAC, 60 Hz and 240 VAC, 50 Hz were tested respectively, but only the worst configuration (120 VAC, 60 Hz) shown here.



Sample No.	S01	Temperature	25.1℃
Humidity	53%RH	Pressure	101kPa
Test Engineer	Yang Yang	Test Date	2024.11.29

Test Mode 1

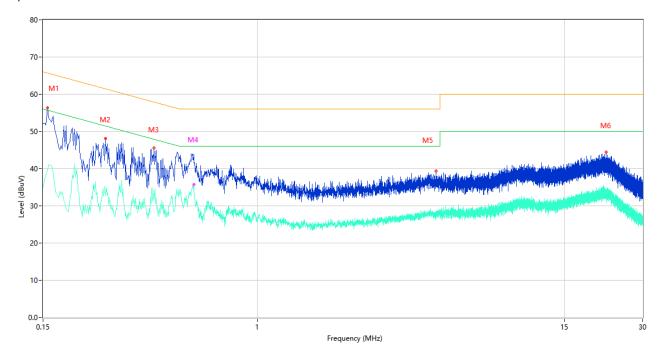
1) AC Ports - L Phase



No.	Frequency	Results	Factor	Limit	Margin	Detector	Line	Verdict
	(MHz)	(dBuV)	(dB)	(dBuV)	(dB)			
1	0.196	47.93	9.77	63.78	15.85	Peak	L	Pass
1**	0.196	39.10	9.77	53.78	14.68	AV	L	Pass
2	0.302	44.43	9.80	60.19	15.76	Peak	L	Pass
2**	0.302	33.24	9.80	50.19	16.95	AV	L	Pass
3	0.524	41.70	10.00	56.00	14.30	Peak	L	Pass
3**	0.524	34.47	10.00	46.00	11.53	AV	L	Pass
4	1.248	38.37	10.44	56.00	17.63	Peak	L	Pass
4**	1.248	27.19	10.44	46.00	18.81	AV	L	Pass
5	4.038	37.75	10.28	56.00	18.25	Peak	L	Pass
5**	4.038	25.45	10.28	46.00	20.55	AV	L	Pass
6	13.158	39.24	10.68	60.00	20.76	Peak	L	Pass
6**	13.158	27.75	10.68	50.00	22.25	AV	L	Pass



2) AC Ports - N Phase



No.	Frequency	Results	Factor	Limit	Margin	Detector	Line	Verdict
	(MHz)	(dBuV)	(dB)	(dBuV)	(dB)			
1	0.156	56.32	9.78	65.67	9.35	Peak	N	Pass
1**	0.156	39.66	9.78	55.67	16.01	AV	N	Pass
2	0.260	48.10	9.76	61.43	13.33	Peak	N	Pass
2**	0.260	32.67	9.76	51.43	18.76	AV	N	Pass
3	0.400	45.49	10.55	57.85	12.36	Peak	N	Pass
3**	0.400	34.19	10.55	47.85	13.66	AV	N	Pass
4	0.568	43.75	10.08	56.00	12.25	Peak	N	Pass
4**	0.568	35.68	10.08	46.00	10.32	AV	N	Pass
5	4.832	39.43	10.14	56.00	16.57	Peak	N	Pass
5**	4.832	27.83	10.14	46.00	18.17	AV	N	Pass
6	21.690	44.44	10.94	60.00	15.56	Peak	N	Pass
6**	21.690	33.81	10.94	50.00	16.19	AV	N	Pass



Equipment Information											
Equipment Name	Supplier	Model	Serial No.	Cal. Date	Cal. Due	Use					
EMI Receiver	KEYSIGHT	N9010B	MY57110309	2024.08.01	2025.07.31	\boxtimes					
LISN	SCHWARZB ECK	NSLK 8127	8127-687	2024.05.09	2025.05.08	\boxtimes					
Shielded Room	YiHeng Electronic Co., Ltd	3.5m*3.1m*2. 8m	112	2022.02.19	2025.02.18						
Description	Supplier	Name	Version	1		Use					
Test Software	BALUN	BL410-E	V22.930	1		\boxtimes					



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ANNEX B TEST SETUP PHOTOS

Please refer the document "BL-SZ24B1408-AE.PDF".

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document "BL-SZ24B1408-AW.PDF".

ANNEX D EUT INTERNAL PHOTOS

Please refer the document "BL-SZ24B1408-AI.PDF".



Statement

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